

15th International Conference on Muon Spin Rotation, Relaxation and Resonance



Contribution ID: 252

Type: Oral

Probing hydrogen sites and negative hyperfine parameter in semiconducting BaSi₂ by muon spin rotation

Thursday, 1 September 2022 15:00 (20 minutes)

Hydrogen passivation of defects is commonly used to reduce defects in semiconductors such as GaAs, diamond, and Si. We recently found by experiment that atomic hydrogen is also very effective in significantly increasing a minority-carrier lifetime ($> 10 \mu\text{s}$) in BaSi₂, one of the emerging materials for thin-film solar cell applications. This means that defects no longer act as recombination centers in BaSi₂ after hydrogen passivation [1-2]. But there has been no experimental data about the hydrogen site in BaSi₂. We employed muons to study the hydrogen state in single-crystalline BaSi₂. Distinct neutral muonium state was identified in the high transverse-field measurements. From the temperature dependence, negative hyperfine parameters were suggested. From the angle-dependence of the hyperfine parameter in the magnetic fields applied in the $a \times b$, $b \times c$, and $c \times a$ planes, and comparison to the calculations based on density-functional theory (DFT), the hydrogen site in the BaSi₂ crystal is proposed.

[1] Z. Xu et al., Phys. Rev. Mater. 3, 065403 (2019).

[2] X. Xu et al., J. Appl. Phys. 127, 233104 (2020).

Primary authors: Prof. SATO, Takuma (Hiroshima University); Dr XU, Zhihao (University of Tsukuba); Dr CAI, Yipeng (TRIUMF and SBQMI, UBC); Dr YOON, Sungwon (TRIUMF and SKKU, Korea); Dr YAMASHITA, Yudai (University of Tsukuba); Dr IMAI, Motoharu (National Institute for Materials Science); Prof. SAITO, Mineo (Kanazawa University); Dr KODA, Akihiro (Institute of Materials Structure Science, High Energy Accelerator Research Organization(KEK)); Prof. SHIMOMURA, Koichiro (KEK); Dr KOJIMA, Kenji (TRIUMF and SBQMI, UBC); Prof. SUEMASU, Takashi (University of Tsukuba)

Presenter: Dr KOJIMA, Kenji (TRIUMF and SBQMI, UBC)

Session Classification: Oral contributions

Track Classification: Semiconductors